

# FDMC8462

## N-Channel Power Trench® MOSFET

### 40V, 20A, 5.8mΩ

#### Features

- Max  $r_{DS(on)}$  = 5.8mΩ at  $V_{GS} = 10V$ ,  $I_D = 13.5A$
- Max  $r_{DS(on)}$  = 8.0mΩ at  $V_{GS} = 4.5V$ ,  $I_D = 11.8A$
- Low Profile - 1mm max in Power 33
- 100% UIL Tested
- RoHS Compliant

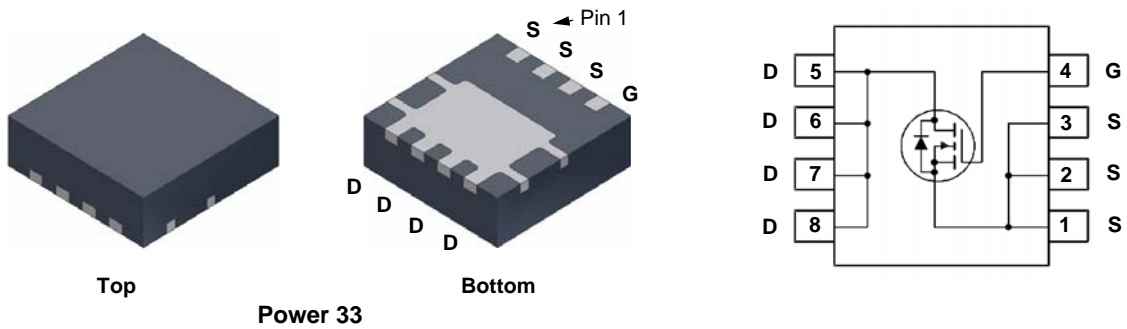


#### General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced Power Trench® process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

#### Application

- DC - DC Conversion



#### MOSFET Maximum Ratings $T_A = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Rated	Units
$V_{DS}$	Drain to Source Voltage	40	V
$V_{GS}$	Gate to Source Voltage	$\pm 20$	V
$I_D$	Drain Current -Continuous (Package limited) $T_C = 25^\circ\text{C}$	20	A
	-Continuous (Silicon limited) $T_C = 25^\circ\text{C}$	64	
	-Continuous $T_A = 25^\circ\text{C}$ (Note 1a)	14	
	-Pulsed	50	
$E_{AS}$	Single Pulse Avalanche Energy (Note 3)	216	mJ
$P_D$	Power Dissipation $T_C = 25^\circ\text{C}$	41	W
	Power Dissipation $T_A = 25^\circ\text{C}$ (Note 1a)	2.0	
$T_J, T_{STG}$	Operating and Storage Junction Temperature Range	-55 to +150	$^\circ\text{C}$

#### Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	3	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	53	

#### Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC8462	FDMC8462	Power 33	13"	12mm	3000 units

## Electrical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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### Off Characteristics

$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}$	40			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , referenced to $25^\circ\text{C}$		31		mV/ $^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{GS} = 0\text{V}, V_{DS} = 32\text{V}$ ,			1	$\mu\text{A}$
$I_{GSS}$	Gate to Source Leakage Current	$V_{GS} = \pm 20\text{V}, V_{DS} = 0\text{V}$			$\pm 100$	nA

### On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250\mu\text{A}$	1.0	2.0	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , referenced to $25^\circ\text{C}$		-6.6		mV/ $^\circ\text{C}$
$r_{DS(on)}$	Static Drain to Source On Resistance	$V_{GS} = 10\text{V}, I_D = 13.5\text{A}$		4.7	5.8	m $\Omega$
		$V_{GS} = 4.5\text{V}, I_D = 11.8\text{A}$		6.4	8.0	
		$V_{GS} = 10\text{V}, I_D = 13.5\text{A}, T_J = 125^\circ\text{C}$		7.1	9.3	
$g_{FS}$	Forward Transconductance	$V_{DD} = 5\text{V}, I_D = 13.5\text{A}$		60		S

### Dynamic Characteristics

$C_{iss}$	Input Capacitance	$V_{DS} = 20\text{V}, V_{GS} = 0\text{V},$ $f = 1\text{MHz}$		2000	2660	pF
$C_{oss}$	Output Capacitance			545	725	pF
$C_{riss}$	Reverse Transfer Capacitance			80	120	pF
$R_g$	Gate Resistance			2.7		$\Omega$

### Switching Characteristics

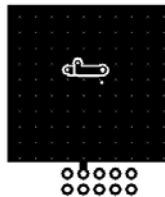
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 20\text{V}, I_D = 13.5\text{A},$ $V_{GS} = 10\text{V}, R_{GEN} = 6\Omega$		12	21	ns
$t_r$	Rise Time			4	10	ns
$t_{d(off)}$	Turn-Off Delay Time			27	43	ns
$t_f$	Fall Time			3	10	ns
$Q_g$	Total Gate Charge	$V_{GS} = 0\text{V to } 10\text{V}$	$V_{DD} = 20\text{V},$ $I_D = 13.5\text{A}$	30	43	nC
$Q_g$	Total Gate Charge	$V_{GS} = 0\text{V to } 4.5\text{V}$		15	21	nC
$Q_{gs}$	Gate to Source Charge			6		nC
$Q_{gd}$	Gate to Drain "Miller" Charge			5		nC

### Drain-Source Diode Characteristics

$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0\text{V}, I_S = 13.5\text{A}$ (Note 2)		0.8	1.3	V
		$V_{GS} = 0\text{V}, I_S = 1.7\text{A}$ (Note 2)		0.7	1.2	
$t_{rr}$	Reverse Recovery Time	$I_F = 13.5\text{A}, di/dt = 100\text{A}/\mu\text{s}$		35	57	ns
$Q_{rr}$	Reverse Recovery Charge			20	32	nC

#### NOTES:

- $R_{\theta JA}$  is determined with the device mounted on a  $1\text{in}^2$  pad 2 oz copper pad on a  $1.5 \times 1.5\text{in.}$  board of FR-4 material.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



a.  $53^\circ\text{C}/\text{W}$  when mounted on a  $1\text{in}^2$  pad of 2 oz copper



b.  $125^\circ\text{C}/\text{W}$  when mounted on a minimum pad of 2 oz copper

- Pulse Test: Pulse Width  $< 300\mu\text{s}$ , Duty cycle  $< 2.0\%$ .
- Starting  $T_J = 25^\circ\text{C}$ ; N-ch:  $L = 3\text{mH}, I_{AS} = 12\text{A}, V_{DD} = 40\text{V}, V_{GS} = 10\text{V}$

**Typical Characteristics**  $T_J = 25^\circ\text{C}$  unless otherwise noted

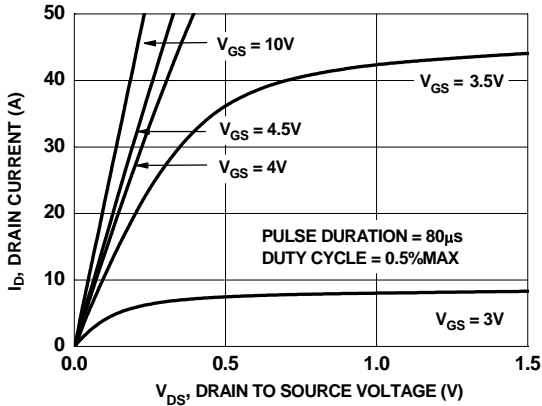


Figure 1. On-Region Characteristics

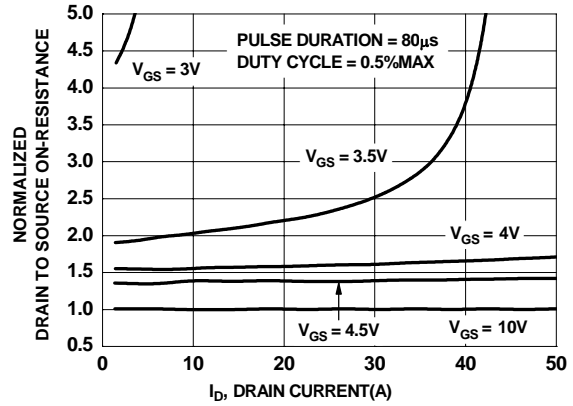


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

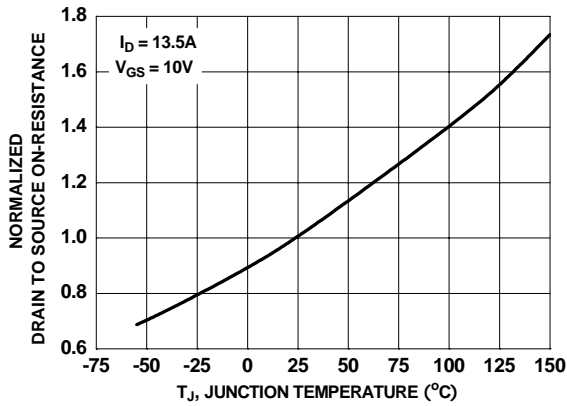


Figure 3. Normalized On-Resistance vs Junction Temperature

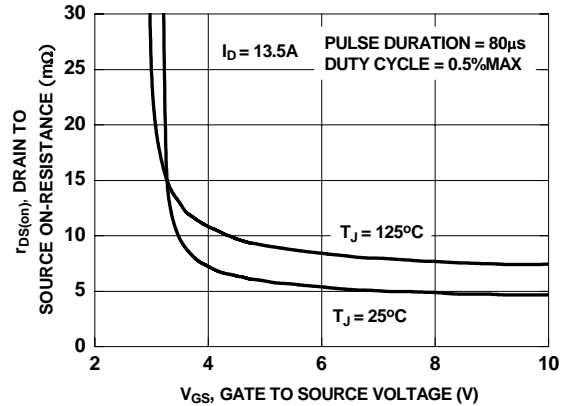


Figure 4. On-Resistance vs Gate to Source Voltage

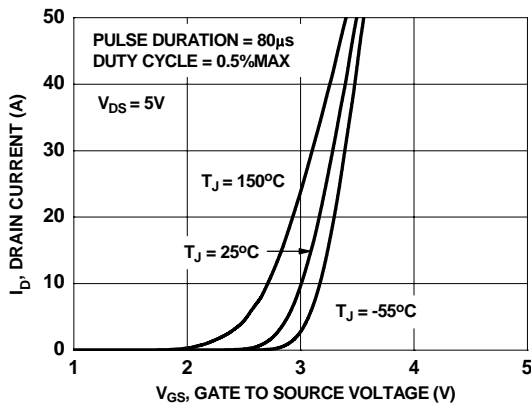


Figure 5. Transfer Characteristics

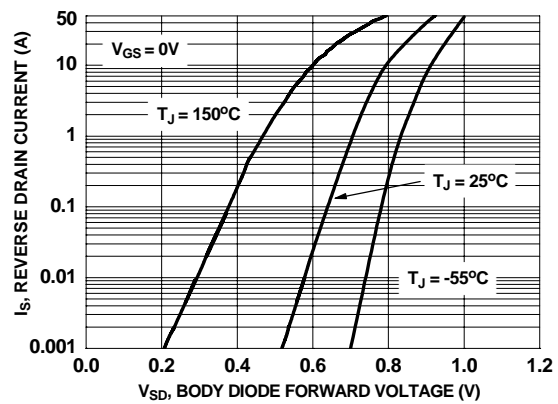
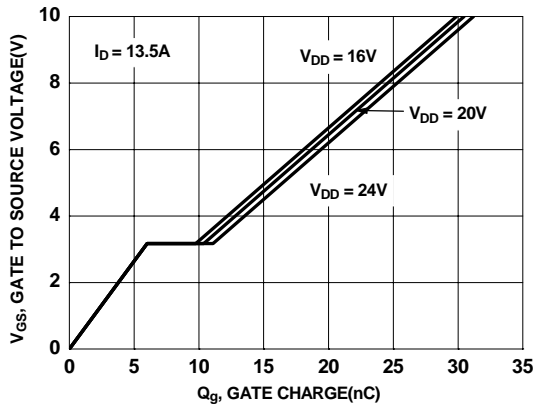
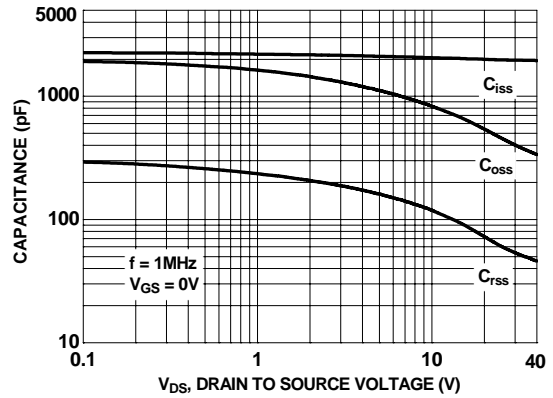


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

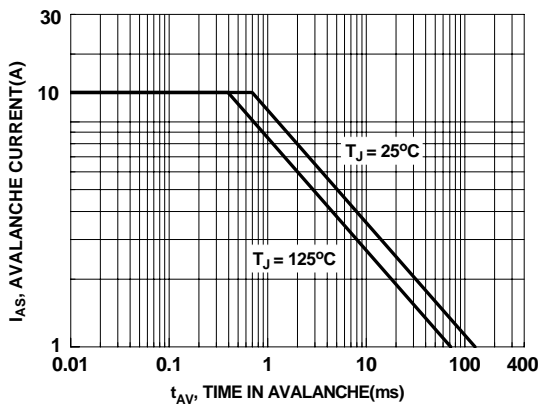
**Typical Characteristics**  $T_J = 25^\circ\text{C}$  unless otherwise noted



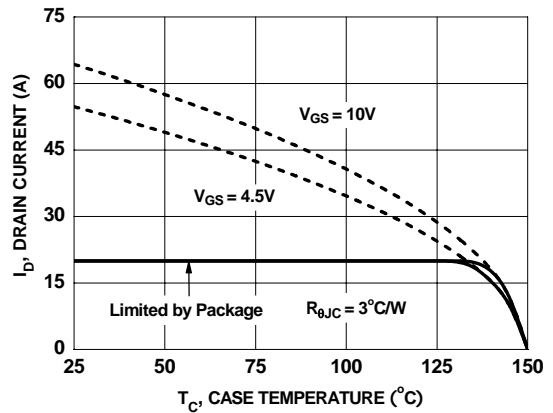
**Figure 7. Gate Charge Characteristics**



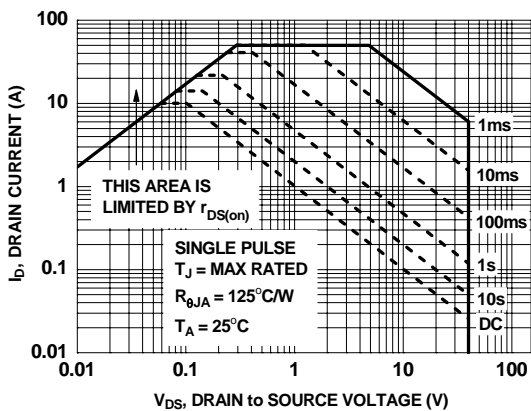
**Figure 8. Capacitance vs Drain to Source Voltage**



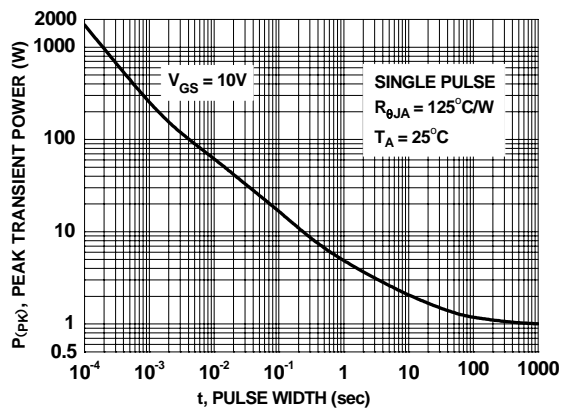
**Figure 9. Unclamped Inductive Switching Capability**



**Figure 10. Maximum Continuous Drain Current vs Case Temperature**

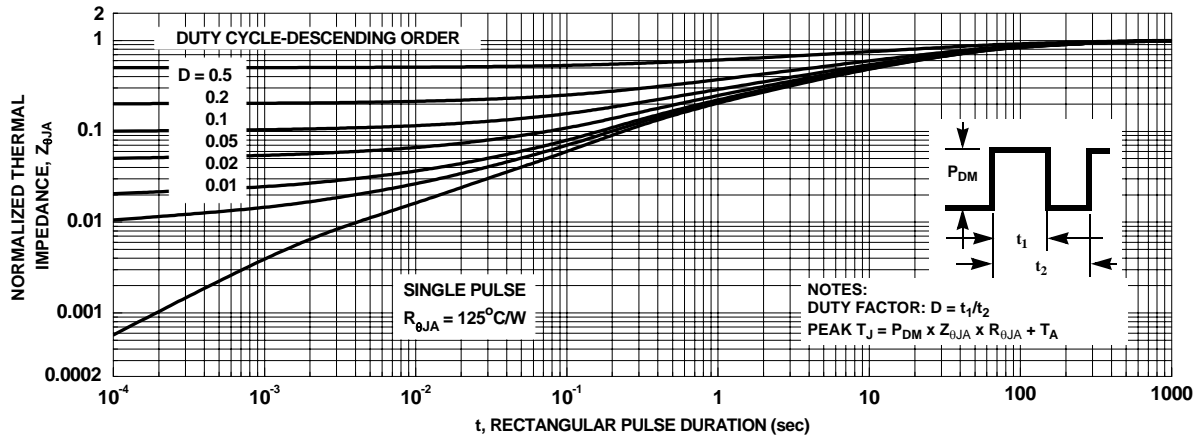


**Figure 11. Forward Bias Safe Operating Area**



**Figure 12. Single Pulse Maximum Power Dissipation**

**Typical Characteristics**  $T_J = 25^\circ\text{C}$  unless otherwise noted






**Figure 13. Transient Thermal Response Curve**





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Rev. I34